Search Notes							

Application/Control No.	Applicant(s)/Patent under Reexamination
10/810,440	MATSUI ET AL.
Examiner	Art Unit
Yong D. Pak	1652

Yong D. Pak

SEARCHED						
Examiner						
ΥP						
YP						
-						

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
stic: seq id no:1	8/10/2005	YP		
stn/east: see search history	8/10/2005	YP		
Inventor search	8/10/2005	YP		